

Product information

Roughness measuring station MarSurf GD 280

Product features

MarSurf GD: The new reference measuring station for roughness and waviness measurements

The new Mahr measuring stations from the MarSurf GD series are setting new standards. In addition to surface roughness evaluations, profile, and waviness evaluations can also be performed. The new MarSurf GD series is enabling production companies to achieve a new dimension to reliably ensure and improve the production quality of workpieces in the measuring room or close to the production area.

The new measuring station concept combines speed, security, and flexibility. The aim is to increase the cost-effectiveness of the system for your company.

The measuring stations are operated with the user-friendly MarWin software (MarWin EasyRoughness or MarWin ProfessionalRoughness).

Application

Mechanical Engineering

Bearings, threads, threaded bars, ball screws, shafts, racks

Production metrology

Contour measurement in a semi-automatic process

Automotive industry

Steering, brake system, gearbox, crankshaft, camshaft, cylinder head

Medical technology

Contour of hip and knee endoprosthesis, contour of medical screws, contour of dental implants



Item no.: 6269012

Technical data

Resolution	Measuring range 1: 2.0 nm Measuring range 2: 0.2 nm
Start of traversing length (in X)	0.1 mm
End of traversing length (in X)	280.0 mm
Traversing length (Lt)	0.1 - 280 mm
Guide deviation	0.20 µm / 60 mm 0.40 µm / 140 mm 0.75 µm / 280 mm
Measuring force (N)	0.7 mN
Measuring speed	0.02 mm/s to 10 mm/s
Positioning speed X-axis min.	0.02 mm/s
positioning speed X-axis max.	200 mm/s
Positioning speed X axis	0.02 - 200 mm/s
Positioning speed Z-axis	0.02 - 50 mm/s
Positioning speed Z axis max.	50 mm/s
Positioning speed Z-axis min.	0.02 mm/s
Probe	Roughness probe system (skidless)
Probe arm length	45 mm (x 1) 67.5 mm (x 1,5) 90 mm (x 2) 112.5 mm (x 2,5) 135 mm (x 3)
Weight (gross)	200 KG
Workpiece weight max.	90 kg
Other functions	manuelle TY
Measuring range mm	500 µm (±250 µm) for probe arm length 45 mm 1500 µm (±750 µm) for probe arm length 135 mm